

Search Notes 	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/020,744	WEISE, JON
	Examiner	Art Unit
	Edgardo San Martin	2837

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
181	129,130	<u>2/14/2005</u>	<u>ESM</u>
	135		